

Analytical methods by nanoAnalytics

The following list gives an overview about the analytical and preparation methods used by us. These methods are available at Münster site directly or provided by partners from long lasting cooperations.



We use following methods :

- Scanning electron microscopy and energy dispersive x-ray microanalysis (SEM / EDS)
- Photo electron spectrometry (ESCA / XPS)
- Secondary ion mass spectrometry (TOF-SIMS)
- Optical interferometer
- Scanning force microscopy (SFM)
- Optical microscopy (fluorescence, polarisation, DIC)
- Contact angle measurements

Additional we offer the following methods to you:

- Infrared spectroscopy and microscopy (FTIR / ATR)
- Transmission electron microscopy (TEM)
- Nano- und Microindentation
- Glow Discharge Optical Emission Spectroscopy (GDOS)
- Secondary Neutral Mass Spectrometry (SNMS)
- Micro computer tomography

Special methods of preparation:

- Cryo fracture
- Ultra microtome
(also under cryo conditions)
- Preparation of cross-sections and targeting polish
- Preparation by Focussed Ion Beam (FIB)